



CERTIFICATION TEST REPORT

Report Number : 4790357232-S2V1

Applicant : SAMSUNG ELECTRONICS CO., LTD.
129 SAMSUNG-RO, YEONGTONG-GU, SUWON-SI,
GYEONGGI-DO, 16677, KOREA

Model : SM-F721B

FCC ID : A3LSMF721B

EUT Description : GSM/WCDMA/LTE/5G NR Phone + BT/BLE, DTS/UNII a/b/g/n/ac/ax,
NFC and WPT

Test Standard(s) : FCC 47 CFR PART 1 SUBPART I
FCC 47 CFR PART 2 SUBPART J

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REPORT REVISION HISTORY

Rev.	Issue Date	Revisions	Revised By
V1	2022-06-15	Initial issue	Sunghoon Kim

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1. ATTESTATION OF TEST RESULTS

COMPANY NAME: SAMSUNG ELECTRONICS CO., LTD.
EUT DESCRIPTION: GSM/WCDMA/LTE/5G NR Phone + BT/BLE, DTS/UNII a/b/g/n/ac/ax, NFC and WPT
MODEL: SM-F721B
SERIAL NUMBER: R3CT504WC5K (RADIATED);
DATE TESTED: 2022-06-14;

APPLICABLE STANDARDS	
STANDARD	TEST RESULTS
FCC PART 1 SUBPART I	Complies
FCC PART 2 SUBPART J	

UL Korea, Ltd. tested the above equipment in accordance with the requirements set forth in the above standards. All indications of Pass/Fail in this report are opinions expressed by UL Korea, Ltd. based on interpretations and/or observations of test results. Measurement Uncertainties were not taken into account and are published for informational purposes only. The test results show that the equipment tested is capable of demonstrating compliance with the requirements as documented in this report.

Note: The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein. This document may not be altered or revised in any way unless done so by UL Korea, Ltd. and all revisions are duly noted in the revisions section. Any alteration of this document not carried out by UL Korea, Ltd. will constitute fraud and shall nullify the document. This report must not be used by the client to claim product certification, approval, or endorsement by IAS, any agency of the Federal Government, or any agency of any government.

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Sunghoon Kim
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UL Korea, Ltd.

2. TEST METHODOLOGY

All calculations were made in accordance with FCC OET Bulletin 65 Edition 97-01.

3. FACILITIES AND ACCREDITATION

The test sites and measurement facilities used to collect data are located at 218 Maeyeong-ro, Yeongtong-gu, Suwon-si, Gyeonggi-do, 16675, Korea. Line conducted emissions are measured only at the 218 address. The following table identifies which facilities were utilized for radiated emission measurements documented in this report. Specific facilities are also identified in the test results sections.

218 Maeyeong-ro
<input checked="" type="checkbox"/> Shield Room 1

UL Korea, Ltd. is accredited by IAS, Laboratory Code TL-637. The full scope of accreditation can be viewed at <https://www.iasonline.org/wp-content/uploads/2017/05/TL-637-cert-New.pdf>.

4. EQUIPMENT UNDER TEST

4.1. DESCRIPTION OF EUT

The EUT has WPT (Wireless Power Transfer) feature which has inductive charging coil to charge phone or watch. The charging frequency is between 110 kHz to 148 kHz, and the maximum power consumption is 9.0 W in charging status.

4.2. WORST-CASE CONFIGURATION

Test configuration	Description
DUT to Phone test configuration 1	Charging from Phone to DUT
DUT to Phone test configuration 2	Charging from Phone to DUT (TA Charging from DUT)
DUT to Phone test configuration 3 (Cross position)	Charging from Phone to DUT
DUT to Phone test configuration 4 (Cross position)	Charging from Phone to DUT (TA Charging from DUT)
DUT to Watch test configuration 5	Charging from Watch to DUT
DUT to Watch test configuration 6	Charging from Watch to DUT (TA Charging from DUT)

Note:

- DUT has two user conditions (DUT Closed & DUT Opened). So Each user conditions are considered for 6 test configurations.
- Configuration 2, 4 and 6 were tested with the worst case of configuration 1, 3 and 5.

4.3. KDB 680106 D01 v03 R01 SECTION 5.b) EQUIPMENT APPROVAL CONSIDERATIONS

Requirement	Device
(1) Power transfer frequency is less than 1 MHz.	Yes. Operating Frequency is between 110kHz to 148 kHz.
(2) Output power from each primary coil is less than or equal to 15 watts.	Yes. Maximum power is 9.0 Watts.
(3) The transfer system includes only single primary and secondary coils. This includes charging systems that may have multiple primary coils and clients that are able to detect and allow coupling only between individual pairs of coils.	Yes.
(4) Client device is placed directly in contact with the transmitter.	Yes.
(5) Mobile exposure conditions only (portable exposure conditions are not covered by this exclusion).	Yes.
(6) The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.	Yes. The aggregate field at 15 cm or 20cm from the device are 8.17 % of the FCC H field limit.

4.4. DESCRIPTION OF TEST SETUP

SUPPORT EQUIPMENT & PERIPHERALS

SUPPROT EQUIPMENT & PERIPHERALS LIST				
Description	Manufacturer	Model	Serial Numver	FCC ID
Phone	Samsung Electronics Co., Ltd.	SM-G986B/DS	R3CMB0C70XN	A3LSMG986B
Watch	Samsung Electronics Co., Ltd.	SM-R835F	RFAM90ZXFTF	A3LSMR835
Traver Adapter	Samsung Electronics Co., Ltd.	EP-TA800	R37N9BV0382HM3	DoC
USB Data Cable	Samsung Electronics Co., Ltd.	EP-DN980BBE	N/A	-

TEST SETUP

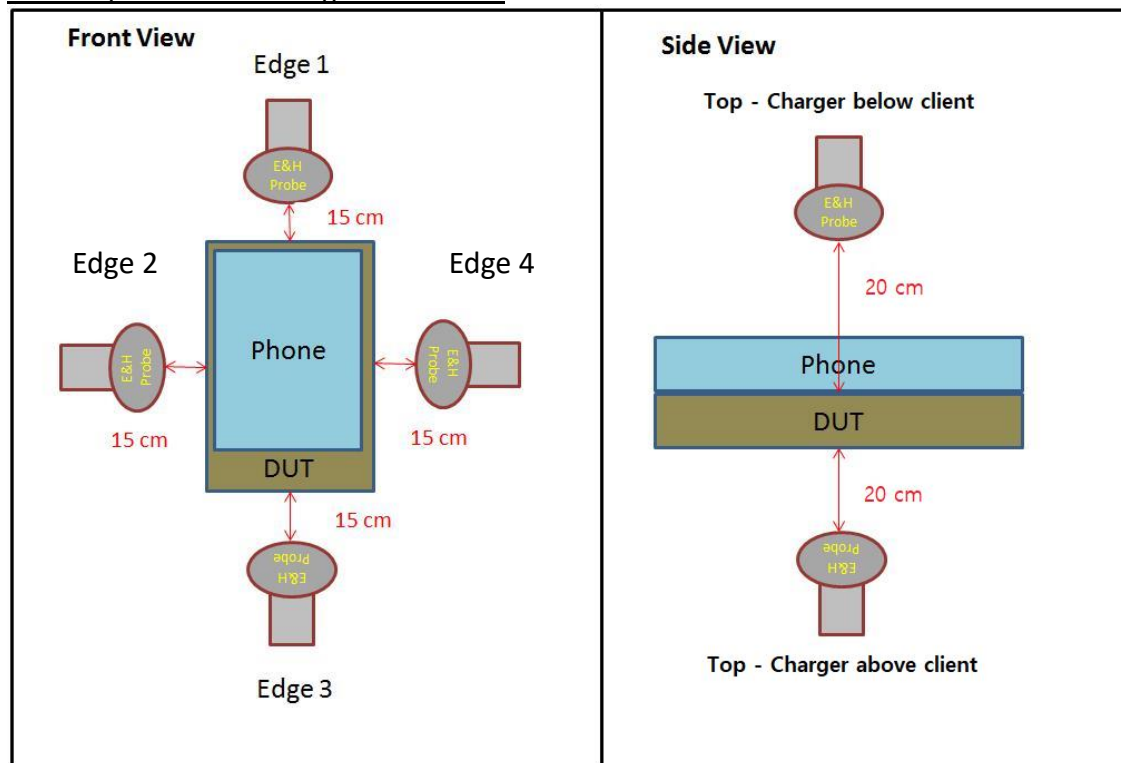
The following three modes are tested in test configurations;

Mode
Operating (SUPPORT Equipment, <10% Power Charging)
Operating (SUPPORT Equipment, 50~55% Power Charging)
Operating (SUPPORT Equipment, 90~95% Power Charging)

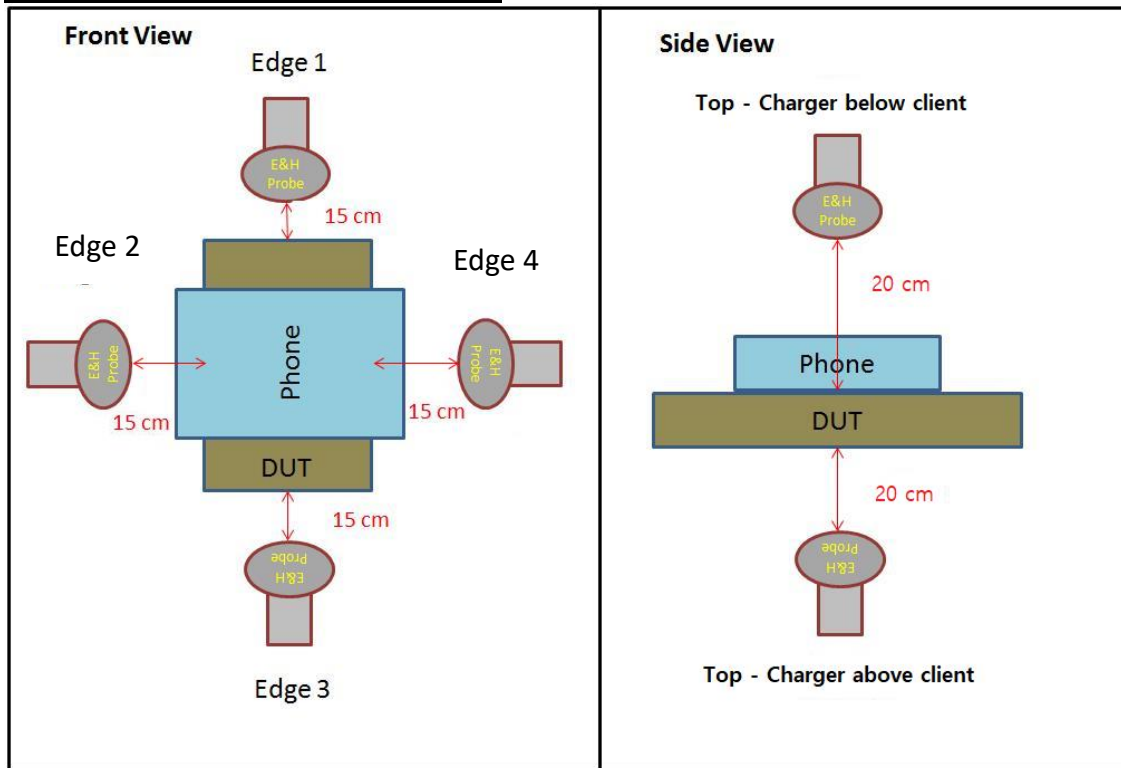
MEASUREMENT TEST SETUP

The measurement was taken using a probe placed 15 cm surrounding the device and 20 cm above the top surface of the EUT. Measurements were taken the top (charger below/above client) and all sides of the EUT per KDB680106 D01 v03 R01 and RF Exposure Procedures (Wireless Power Transfer) in TCB Workshop October, 2018.

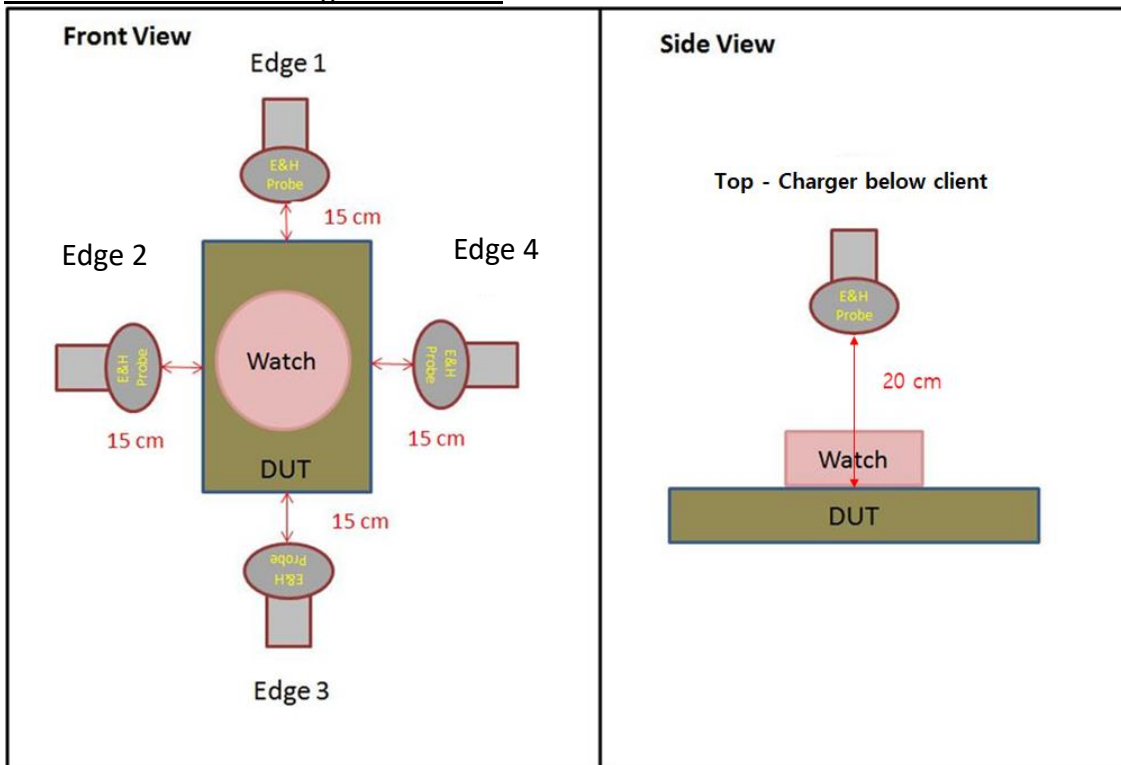
DUT to phone test Configuration 1 & 2



DUT to phone test Configuration 3 & 4



DUT to Watch test Configuration 5 & 6



5. TEST AND MEASUREMENT EQUIPMENT

The following test and measurement equipment was used for the tests documented in this report;

Test Equipment List				
Description	Manufacturer	Model	S/N	Cal Due
E-H Field Analyzer	Narda	EHP-200AC	170WX91008	2022-08-06

6. Maximum PERMISSIBLE RF EXPOSURE

6.1. FCC LIMITS AND SUMMARY

6.1.1. FCC LIMITS

§ 1.1310 The criteria listed in Table 1 shall be used to evaluate the environmental impact of human exposure to radio-frequency (RF) radiation as specified in § 1.1307(b), except in the case of portable devices which shall be evaluated according to the provisions of § 2.1093 of this chapter.

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
(A) Limits for Occupational/Controlled Exposures				
0.3–3.0	614	1.63	*(100)	6
3.0–30	1842/f	4.89/f	*(900/f ²)	6
30–300	61.4	0.163	1.0	6
300–1500	f/300	6
1500–100,000	5	6
(B) Limits for General Population/Uncontrolled Exposure				
0.3–1.34	614	1.63	*(100)	30
1.34–30	824/f	2.19/f	*(180/f ²)	30

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)—Continued

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
30–300	27.5	0.073	0.2	30
300–1500	f/1500	30
1500–100,000	1.0	30

f = frequency in MHz

* = Plane-wave equivalent power density

NOTE 1 TO TABLE 1: Occupational/controlled limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occupational/controlled limits apply provided he or she is made aware of the potential for exposure.

NOTE 2 TO TABLE 1: General population/uncontrolled exposures apply in situations in which the general public may be exposed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure or can not exercise control over their exposure.

6.2. TEST RESULTS

6.2.1. FCC RF EXPOSURE

H-FIELD MEASUREMENTS

Note: Peak measurement were performed.

Additional test was performed in each Test mode by moving the probe surrounding the device to find the maximum exposure.

Case.1 : DUT opened configuration

TEST results of DUT to phone test Configuration 1 & 2

FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)
Configuration 1	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger above client	1.63	0.0305
			Top - charger below client		0.0296
			Edge 1		0.0303
			Edge 2		0.0361
			Edge 3		0.0597
			Edge 4		0.0468
	Max		0.0597		
	Operating Real Product (Power 50~55% charging)		Top - charger above client		0.0293
			Top - charger below client		0.0301
			Edge 1		0.0317
			Edge 2		0.0370
			Edge 3		0.0590
			Edge 4		0.0452
	Operating Real Product (Power 90~95% charging)		Max		0.0590
			Top - charger above client		0.0302
			Top - charger below client		0.0305
			Edge 1		0.0309
			Edge 2		0.0363
Edge 3		0.0580			
Configuration 2	Operating Real Product (Power <10% charging)	Edge 4	0.0470		
		Max	0.0580		
		Edge 3	0.0501		

TEST results of DUT to phone test Configuration 3 & 4

FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)
Configuration 3	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger above client	1.63	0.0297
			Top - charger below client		0.0306
			Edge 1		0.0314
			Edge 2		0.0819
			Edge 3		0.0430
			Edge 4		0.0445
	Max		0.0819		
	Operating Real Product (Power 50~55% charging)		Top - charger above client		0.0351
			Top - charger below client		0.0297
			Edge 1		0.0387
			Edge 2		0.0780
			Edge 3		0.0423
			Edge 4		0.0454
	Operating Real Product (Power 90~95% charging)		Max		0.0780
			Top - charger above client		0.0365
			Top - charger below client		0.0308
			Edge 1		0.0366
			Edge 2		0.0773
Edge 3		0.0430			
Configuration 4	Operating Real Product (Power <10% charging)	Edge 4	0.0410		
		Max	0.0773		
		Edge 2	0.0751		

TEST results of DUT to phone test Configuration 5 & 6

FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)
Configuration 5	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger below client	1.63	0.1245
			Edge 1		0.0317
			Edge 2		0.0308
			Edge 3		0.0332
			Edge 4		0.0400
			Max		0.1245
	Operating Real Product (Power 50~55% charging)		Top - charger below client		0.1332
			Edge 1		0.0305
			Edge 2		0.0301
			Edge 3		0.0376
			Edge 4		0.0387
			Max		0.1332
	Operating Real Product (Power 90~95% charging)		Top - charger below client		0.1287
			Edge 1		0.0305
			Edge 2		0.0320
			Edge 3		0.0336
			Edge 4		0.0341
			Max		0.1287
Configuration 6	Operating Real Product (Power 50~55% charging)		Top - charger below client		0.1322

Case.2 : DUT Closed configuration

TEST results of DUT to phone test Configuration 1 & 2

FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)
Configuration 1	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger above client	1.63	0.0293
			Top - charger below client		0.0293
			Edge 1		0.0353
			Edge 2		0.0305
			Edge 3		0.0647
			Edge 4		0.0509
			Max		0.0647
	Operating Real Product (Power 50~55% charging)		Top - charger above client		0.0305
			Top - charger below client		0.0284
			Edge 1		0.0339
			Edge 2		0.0296
			Edge 3		0.0646
			Edge 4		0.0503
			Max		0.0646
	Operating Real Product (Power 90~95% charging)		Top - charger above client		0.0296
			Top - charger below client		0.0305
			Edge 1		0.0317
			Edge 2		0.0297
			Edge 3		0.0582
			Edge 4		0.0425
			Max		0.0582
Configuration 2	Operating Real Product (Power <10% charging)		Edge 3		0.0554

TEST results of DUT to phone test Configuration 3 & 4

FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)
Configuration 3	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger above client	1.63	0.0305
			Top - charger below client		0.0293
			Edge 1		0.0296
			Edge 2		0.0603
			Edge 3		0.0305
			Edge 4		0.0436
			Max		0.0603
	Operating Real Product (Power 50~55% charging)		Top - charger above client		0.0296
			Top - charger below client		0.0305
			Edge 1		0.0305
			Edge 2		0.0608
			Edge 3		0.0303
			Edge 4		0.0430
			Max		0.0608
	Operating Real Product (Power 90~95% charging)		Top - charger above client		0.0317
			Top - charger below client		0.0296
			Edge 1		0.0306
			Edge 2		0.0588
			Edge 3		0.0296
			Edge 4		0.0434
			Max		0.0588
Configuration 4	Operating Real Product (Power 50~55% charging)		Edge 2		0.0491

TEST results of DUT to phone test Configuration 5 & 6
FCC RF Exposure Result

Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas. data (A/m)
Configuration 5	Operating Real Product (Power <10% charging)	15 cm probe to edges of EUT and 20 cm probe to top surface of the EUT	Top - charger below client	1.63	0.0305
			Edge 1		0.0311
			Edge 2		0.0308
			Edge 3		0.0293
			Edge 4		0.0305
			Max		0.0311
	Operating Real Product (Power 50~55% charging)		Top - charger below client		0.0293
			Edge 1		0.0340
			Edge 2		0.0305
			Edge 3		0.0314
			Edge 4		0.0308
			Max		0.0340
	Operating Real Product (Power 90~95% charging)		Top - charger below client		0.0317
			Edge 1		0.0315
			Edge 2		0.0308
Edge 3		0.0296			
Edge 4		0.0296			
Max		0.0317			
Configuration 6	Operating Real Product (Power 50~55% charging)		Edge 1		0.0305

6.2.2. FCC SUMMARY OF RESULTS

H-Field Limit		
FCC RF Exposure	Maximum meas data (A/m)	Percentage (%)
1.63	0.1332	8.17

Conclusion:

H-Field result is less than 50% of the MPE limit.

END OF TEST REPORT